

Issue Classification 		Application/Control No.		Applicant(s)/Patent under Reexamination	
		10/776,286		ONOZAWA ET AL.	
Examiner		Art Unit			
		Leith A. Al-Nazer		2821	

ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
345	55	345	60	204			
INTERNATIONAL CLASSIFICATION		315	169.1	169.2	169.3	169.4	
G 0 9	G 3/20						
G 0 9	G 3/28						
G 0 9	G 3/10						
	/						
	/						
Leith A. Al-Nazer 2/27/06		Don Wong 3/3/06					Total Claims Allowed: 3
(Assistant Examiner) (Date)		(Primary Examiner) (Date)					O.G. Print Claim(s) 1
Q. Brown 3/8/06		DON WONG SUPERVISORY PATENT EXAMINER					O.G. Print Fig. 7
(Legal Instruments Examiner) (Date)							

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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